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(12) **United States Design Patent**
Terada et al.

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(45) **Date of Patent: ** Sep. 18, 2001**

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(54) **MEASURING APPARATUS FOR MEASURING A PARTICLE SIZE DISTRIBUTION**

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(73) Assignee: **Sysmex Corporation**, Kobe (JP)

(**) Term: **14 Years**

(21) Appl. No.: **29/132,403**

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(51) **LOC (7) Cl.** **10-04**
(52) **U.S. Cl.** **D10/75**; D10/46
(58) **Field of Search** D10/46, 75; 250/575; 356/336–338

(56) **References Cited**

U.S. PATENT DOCUMENTS

6,191,853 * 2/2001 Yamaguchi et al. 356/336

* cited by examiner

Primary Examiner—Antoine Duval Davis
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(57) **CLAIM**

The ornamental design for a measuring apparatus for measuring a particle size distribution, as shown and described.

DESCRIPTION

FIG. **1** is a front view of a measuring apparatus for measuring a particle size distribution showing our new design;

FIG. **2** is a rear view thereof;

FIG. **3** is a left side view thereof;

FIG. **4** is a right side view thereof;

FIG. **5** is a top plan view thereof; and,

FIG. **6** is a bottom plan view thereof.

1 Claim, 6 Drawing Sheets

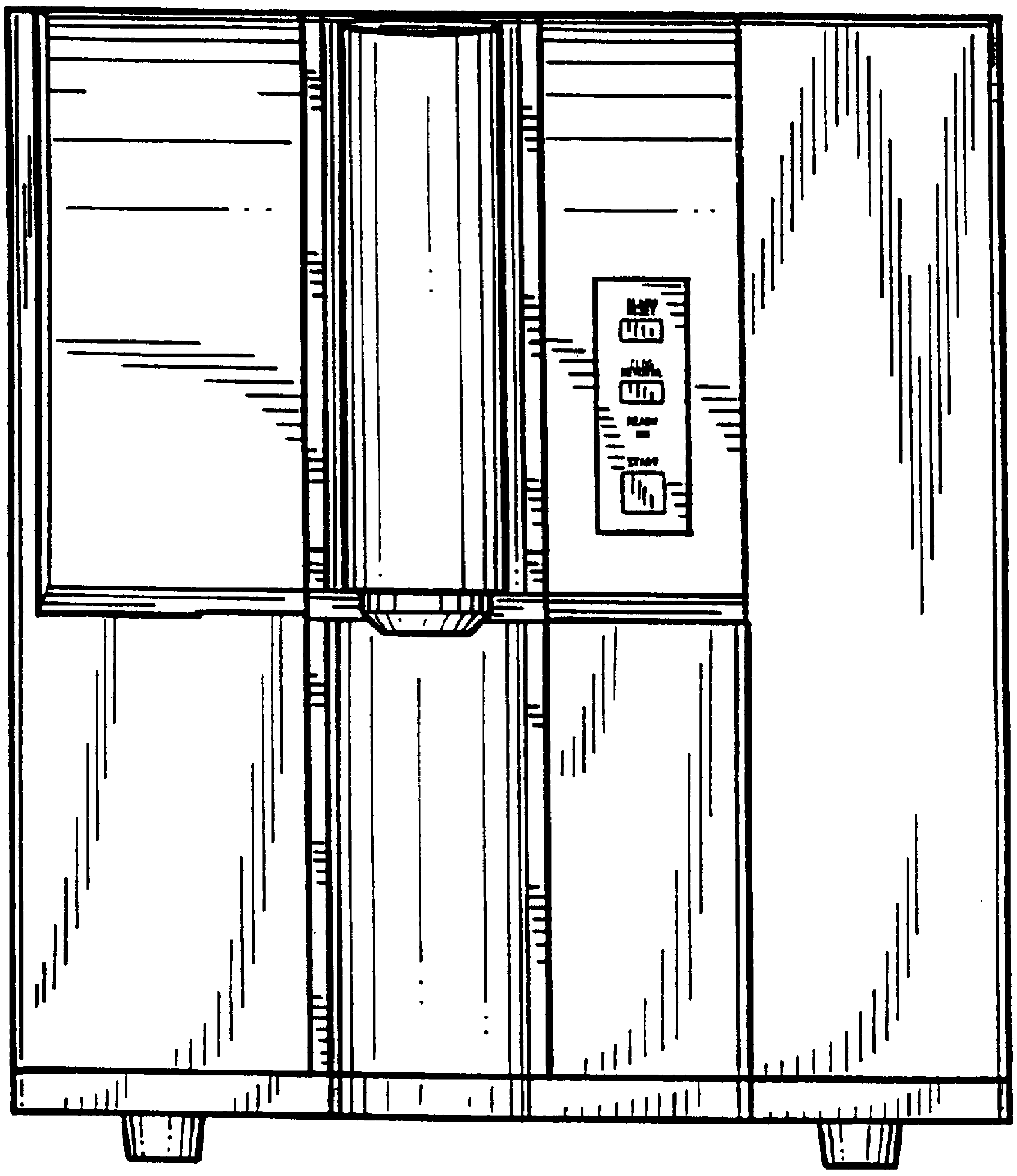

FIG. 1

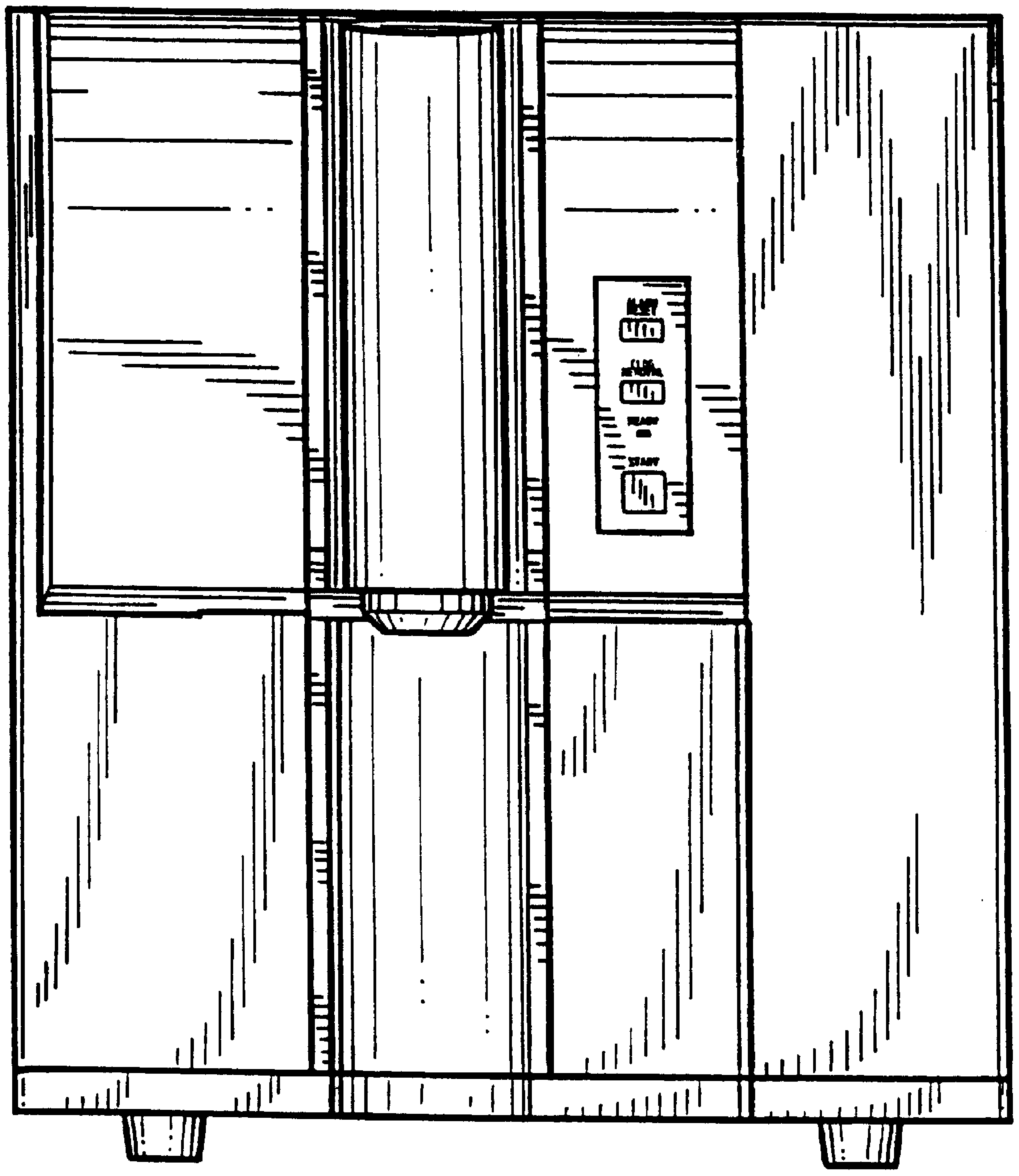

FIG. 2

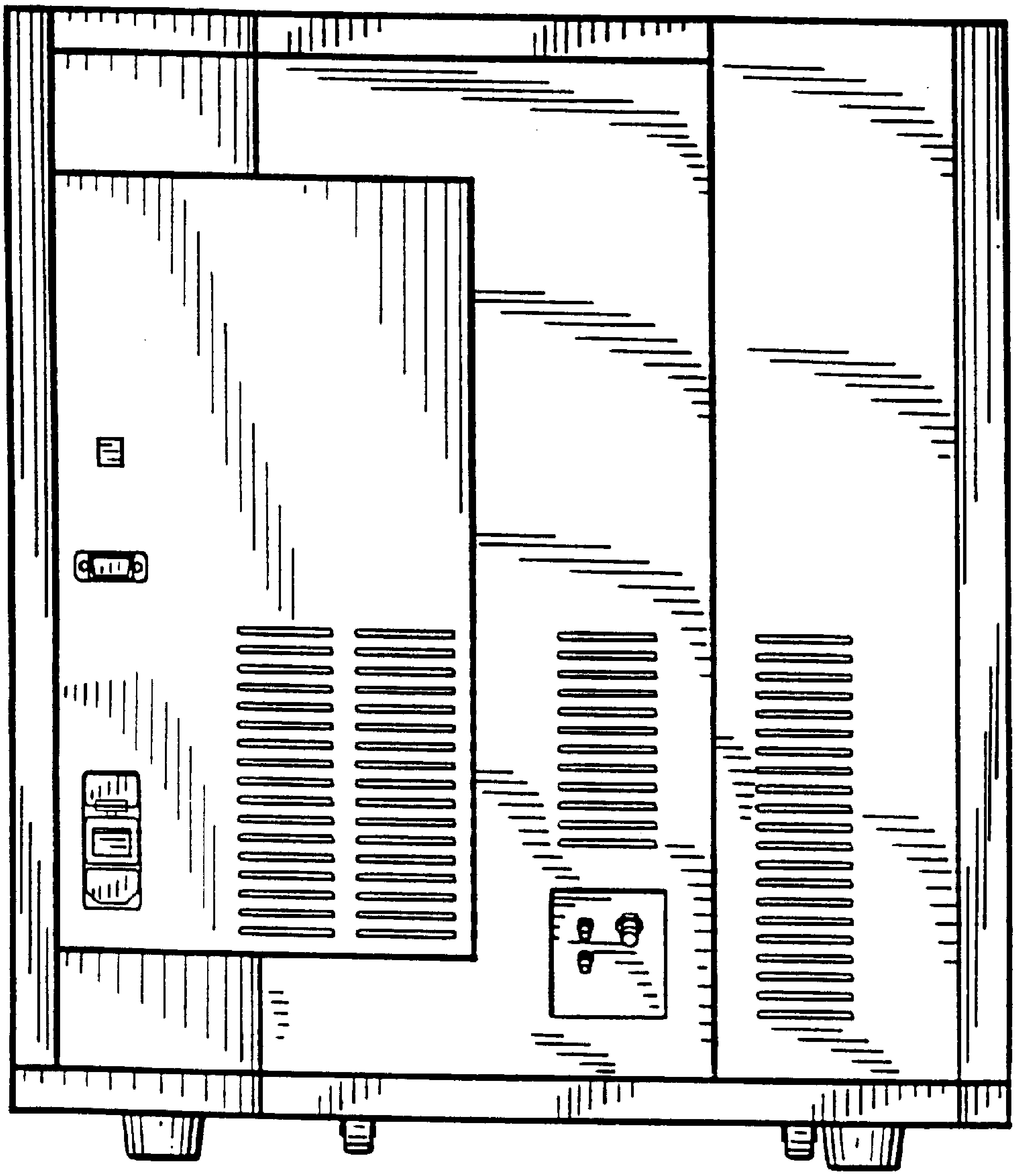

FIG. 3

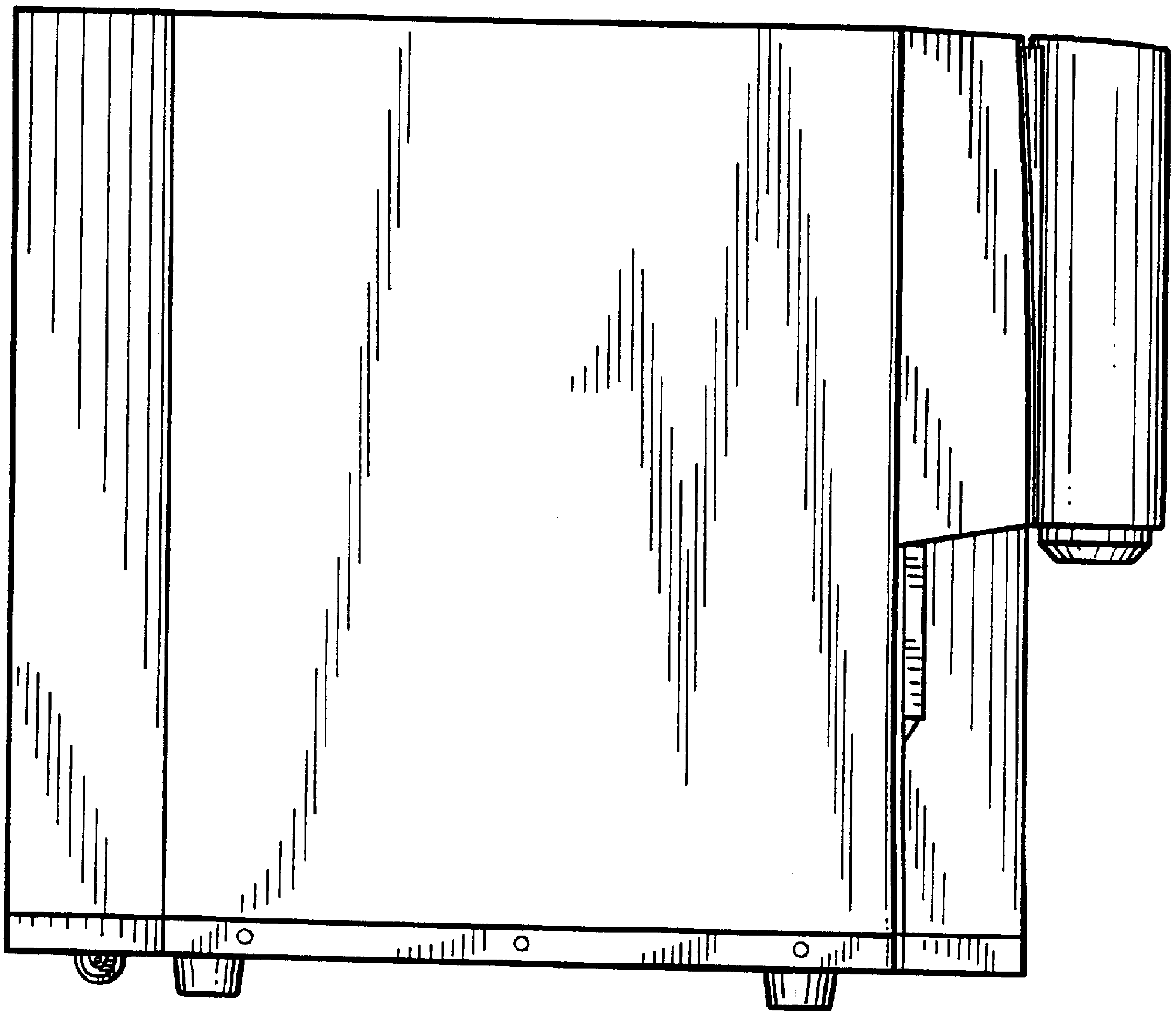

FIG. 4

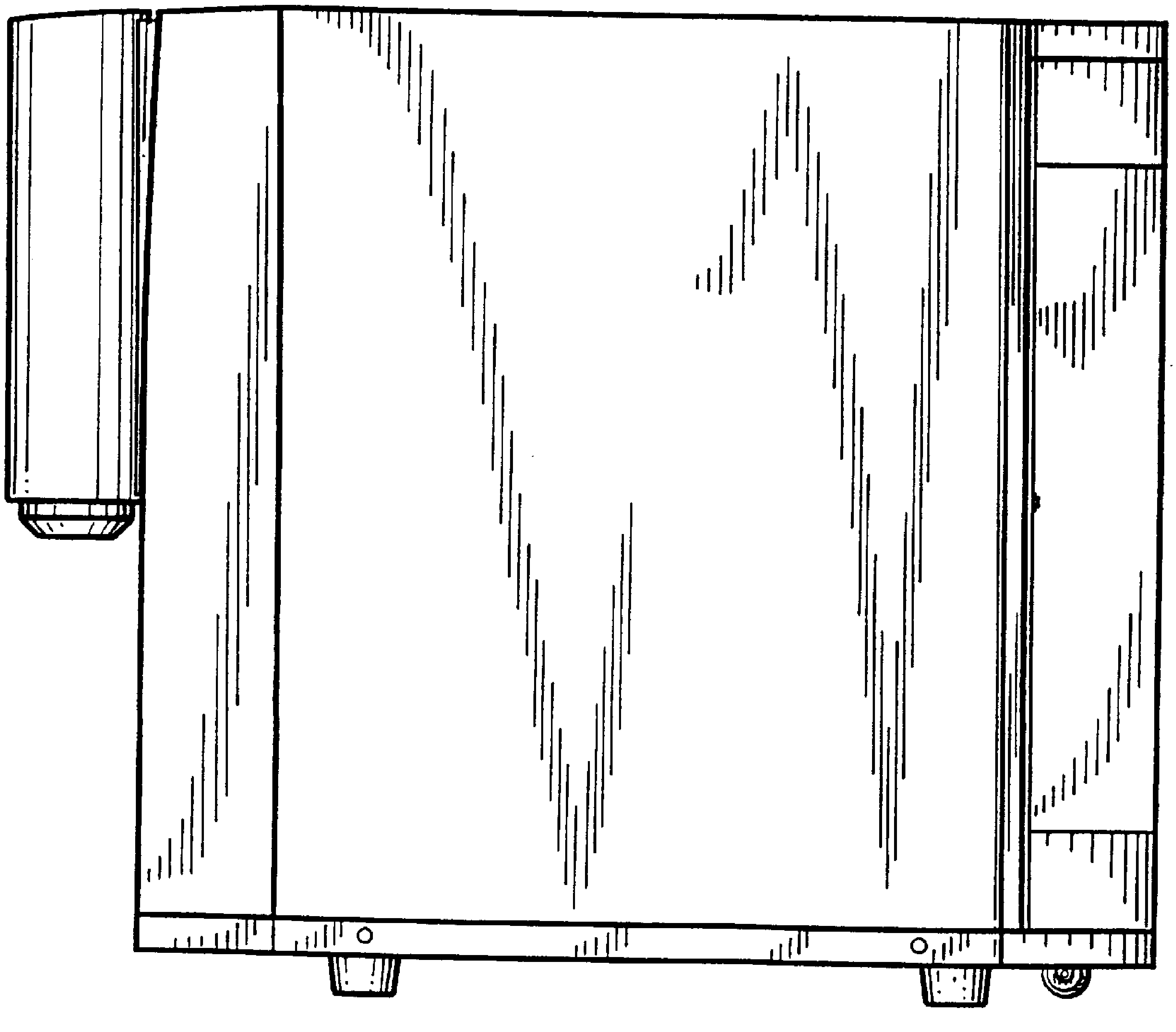

FIG. 5

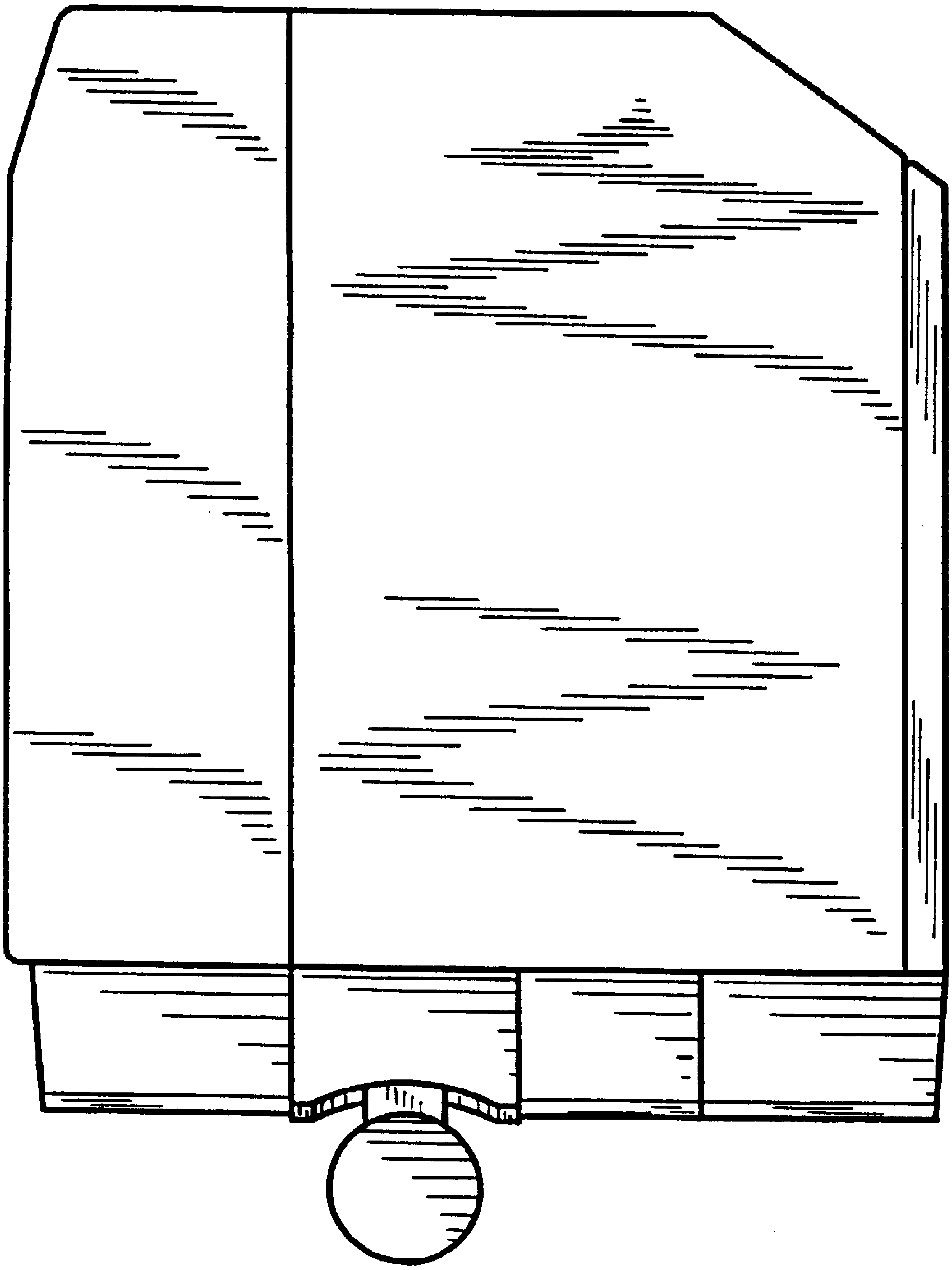

FIG. 6